July 2003

FDW9926A

FAIRCHILD SEMICONDUCTOR

Dual N-Channel 2.5V Specified PowerTrench^o MOSFET

General Description

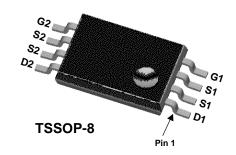
This N-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V - 10V).

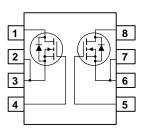
Applications

- Battery protection
- Load switch
- Power management

Features

- 4.5 A, 20 V. $R_{DS(ON)} = 32 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ $R_{DS(ON)} = 45 \text{ m}\Omega @ V_{GS} = 2.5 \text{ V}$
- Optimized for use in battery circuit applications
- Extended V_{GSS} range (±10V) for battery applications
- + High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol		Parameter		Ratings	Units
V _{DSS}	Drain-Sour	ce Voltage		20	V
V _{GSS}	Gate-Sourc	e Voltage		±10	V
ID	Drain Curre	ent – Continuous	(Note 1a)	4.5	A
		- Pulsed		30	
P _D	Total Powe	r Dissipation	(Note 1a)	1.0	W
			(Note 1b)	0.6	
T _J , T _{STG}	Operating a	and Storage Junction Tempe	rature Range	-55 to +150	°C
T I:	•				•
inerma	al Charac	teristics			
		teristics esistance, Junction-to-Ambie	nt (Note 1a)	125	°C/W
			nt (Note 1a) (Note 1b)	125 208	°C/W
$R_{\theta JA}$	Thermal Re		(Note 1b)		°C/W
R _{eja} Packag	Thermal Re	sistance, Junction-to-Ambie g and Ordering In	(Note 1b)		°C/W

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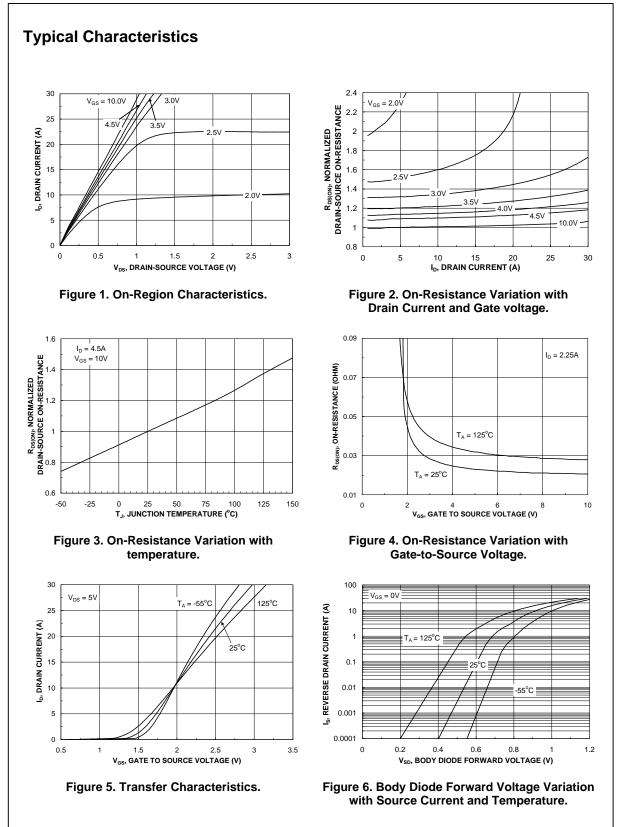
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics	-				
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = 250 \mu A$	20			V
<u>ΔBV_{DSS}</u> ΔTJ	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C		12		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 16 V$, $V_{GS} = 0 V$			1	μA
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			±100	nA
On Chara	Acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	0.6	1.0	1.5	V
$\Delta V_{GS(th)}$ ΔT_{J}	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		-3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{GS} = 4.5 \ V, & I_D = 4.5 \ A \\ V_{GS} = 2.5 \ V, & I_D = 3.8 \ A \\ V_{GS} = 4.5 \ V, I_D = 4.5 \ A, \ T_J = 125^\circ C \end{array} $		24 34 33	32 45 48	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 4.5 V, N_{DS} = 5 V$	15	- 55	40	A
. ,	Forward Transconductance	$V_{DS} = 5 V$, $I_D = 4.5 A$	10	19		s
g _{FS}	Characteristics	$v_{DS} = 3 v$, $v_{D} = 4.0 A$		13		5
	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$		630	1	pF
	Output Capacitance	$V_{DS} = 10 V$, $V_{GS} = 0 V$, f = 1.0 MHz		150		pF
C _{rss}	Reverse Transfer Capacitance			85		pF
R _G	Gate Resistance	V _{GS} = 15 mV, f = 1.0 MHz		1.4		Ω
Switchin	g Characteristics (Note 2)		I			
t _{d(on)}	Turn–On Delay Time	$V_{DD} = 10 \text{ V}, I_D = 1 \text{ A},$		8	16	ns
(),	Turn–On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		8	16	ns
d(off)	Turn-Off Delay Time	-		15	26	ns
tr	Turn–Off Fall Time	-		4	8	ns
Q _g	Total Gate Charge	$V_{DS} = 10 V$, $I_D = 4.5 A$,		6.1	9	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 4.5 V		1.1		nC
Q _{gd}	Gate-Drain Charge	_		1.8		nC
Drain-So	ource Diode Characteristics a	and Maximum Ratings	•		•	•
Is	Maximum Continuous Drain-Source				0.83	A
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = 0.83 A$ (Note 2)		0.69	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 4.5 A,		14		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$	<u> </u>	4	1	nC

1. R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.

a) R_{θJA} is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4.
b) R_{θJA} is 208 °C/W (steady state) when mounted on a minimum copper pad on FR-4.

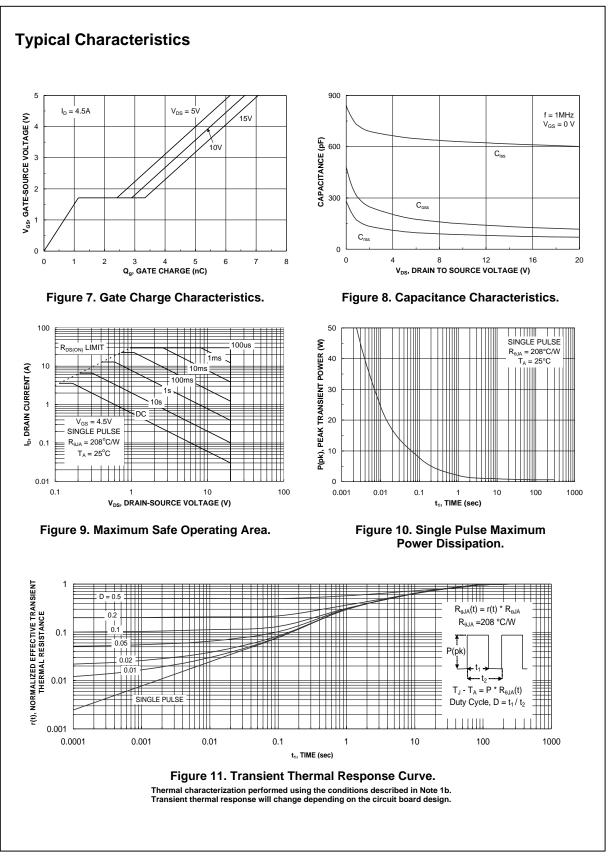
2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

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FDW9926A Rev. D (W)



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Programmable A		POP™	SuperSOT™-3	

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